

Notice of References Cited	Application/Control No. 09/385,666	Applicant(s)/Patent Under Reexamination SUAYA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Chen et al, "An On-Chip, Attofarad Interconnect Charge-based Capacitance Measurement Technique", IEEE, 1996, pp. 3.4.1-3.4.4.
*	V	Sylvester et al, "Investigation of Interconnect Capacitance Characterization using Charge-based Capacitance Measurement Technique and 3-D Simulation", IEEE, 1997, pp. 491-494.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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